

# Deutsche Akkreditierungsstelle

# Annex to the Partial Accreditation Certificate D-K-15105-01-01 according to DIN EN ISO/IEC 17025:2018

Valid from: 30.10.2023

Date of issue: 30.10.2023

This annex is a part of the accreditation certificate D-K-15105-01-00.

Holder of partial accreditation certificate:

## WIKA Alexander Wiegand SE & Co. KG Alexander-Wiegand-Straße 30, 63911 Klingenberg

with the location:

## WIKA Alexander Wiegand SE & Co. KG Alexander-Wiegand-Straße 30, 63911 Klingenberg

The calibration laboratory meets the requirements of DIN EN ISO/IEC 17025:2018 to carry out the conformity assessment activities listed in this annex. The calibration laboratory meets additional legal and normative requirements, if applicable, including those in relevant sectoral schemes, provided that these are explicitly confirmed below.

The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of calibration laboratories and confirm generally with the principles of DIN EN ISO 9001.

Calibration in the fields:

## **Electrical quantities**

- DC and low frequency quantities
- DC voltage
- DC current
- DC resistance

This certificate annex is only valid together with the written accreditation certificate and reflects the status as indicated by the date of issue. The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at https://www.dakks.de.

Abbreviations used: see last page

Page 1 of 2 This document is a translation. The definitive version is the original German annex to the accreditation certificate.



### Annex to the Partial Accreditation Certificate D-K-15105-01-01

#### Permanent Laboratory

### Calibration and Measurement Capabilities (CMC)

Measured quantity / Calibration item	Range		Measurement conditions / procedure	Best measurement capability	Remarks
DC voltage Measuring instruments and sources	0V to	0.2 V		$20 \cdot 10^{-6} \cdot U + 1 \mu V$	U = measured value
	> 0.2 V to	2.0 V		11 · 10 <sup>-6</sup> · <i>U</i> + 2 μV	
	> 2.0 V to	20 V		12 · 10 <sup>-6</sup> · <i>U</i> + 20 μV	
	> 20 V to	100 V		18 · 10 <sup>-6</sup> · <i>U</i> + 0,15 mV	
DC current Measuring instruments and sources	0 mA to	20 mA		13 · 10 <sup>-6</sup> · / + 50 nA	<i>I</i> = measured value
	> 20 mA to	100 mA		36 · 10 <sup>-6</sup> · / + 0,9 μΑ	
DC resistance Measuring instruments and sources	$0\Omega$ to	110 Ω		40 · 10 <sup>-6</sup> · <i>R</i> + 1,5 m $\Omega$	R = measured value
	$> 110 \Omega$ to	1.1 kΩ		$28 \cdot 10^{-6} \cdot R + 2 \mathrm{m}\Omega$	
	>1.1 kΩ to	10 kΩ		$28 \cdot 10^{-6} \cdot R + 20 \ \mathrm{m}\Omega$	
Measuring instruments	10 Ω, 25 Ω, 100 Ω, 450 Ω, 1,0 kΩ, 45 kΩ, 500 kΩ			10 · 10 <sup>-6</sup> · <i>R</i>	R = measured value

#### Abbreviations used:

CMC Calibration and measurement capabilities